Low-Voltage, Single and Dual Supply, Quad SPDT, Analog Switches

The Intersil ISL8394 device is a precision, quad SPDT analog switches designed to operate from a single +2V to +12V supply or from a ±2V to ±6V supply. Targeted applications include battery powered equipment that benefit from the devices' low power consumption (5μW), low leakage currents (2.5nA max), and fast switching speeds (t_{ON} = 50ns, t_{OFF} = 30ns). A 4Ω maximum R_{ON} flatness ensures signal fidelity, while channel to channel mismatch is guaranteed to be less than 2Ω.

The ISL8394 is a quad single-pole/double-throw (SPDT) device and can be used as a quad SPDT, a quad 2:1 multiplexer, a single 4:1 multiplexer, or a dual 2-channel differential multiplexer.

Table 1 summarizes the performance of this family. For higher performance, pin compatible versions, see the ISL43240 data sheet.

TABLE 1. FEATURES AT A GLANCE

	ISL8394
Configuration	Quad SPDT
±5V R_{ON}	17Ω
±5V t_{ON}/t_{OFF}	50ns/30ns
5V R_{ON}	25Ω
5V t_{ON}/t_{OFF}	80ns/40ns
3V R_{ON}	75Ω
3V t_{ON}/t_{OFF}	150ns/75ns
Package	20 Ld SOIC

Ordering Information

PART NO. (BRAND)	TEMP. RANGE (°C)	PACKAGE	PKG. DWG. #
ISL8394IB	-40 to 85	20 Ld SOIC	M20.3
ISL8394IB-T	-40 to 85	20 Ld SOIC Tape and Reel	M20.3

Features

- Drop-in Replacement for MAX394

- Four Separately Controlled SPDT Switches

- ON Resistance (R_{ON}) . . . . 17Ω (Typ) 35Ω (Max)

- R_{ON} Matching Between Channels. . . . .<1Ω

- Low Charge Injection . . . . 10pC (Max)

- Low Power Consumption (P_D). . . . .<5μW

- Low Leakage Current (Max at 85°C) 2.5nA

- Fast Switching Action
  - t_{ON} 50ns
  - t_{OFF} 30ns

- Guaranteed Break-Before-Make

- Minimum 2000V ESD Protection per Method 3015.7

- TTL, CMOS Compatible

Applications

- Battery Powered, Handheld, and Portable Equipment
  - Barcode Scanners
  - Laptops, Notebooks, Palmtops

- Communications Systems
  - Radios
  - Base Stations
  - RF "Tee" Switches

- Test Equipment
  - Ultrasound
  - CAT/PET SCAN
  - Electrocardiograph

- Audio and Video Switching

- General Purpose Circuits
  - +3V/+5V DACs and ADCs
  - Digital Filters
  - Operational Amplifier Gain Switching Networks
  - High Frequency Analog Switching
  - High Speed Multiplexing

Related Literature

- Technical Brief TB363 "Guidelines for Handling and Processing Moisture Sensitive Surface Mount Devices (SMDs)"

- Application Note AN557 "Recommended Test Procedures for Analog Switches"

Pinout (Note 1)

ISL8394 (SOIC)
TOP VIEW

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IN1   [1]              [20]  IN4
NO1   [2]              [19]  NO4
COM1  [3]              [18]  COM4
NC1   [4]              [17]  NC4
V-    [5]              [16]  V+
GND   [6]              [15]  N.C.
NC2   [7]              [14]  NC3
COM2  [8]              [13]  COM3
NO2   [9]              [12]  NO3
IN2   [10]             [11]  IN3
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NOTE:

1. Switches Shown for Logic "0" Input.

Truth Table

LOGIC	ISL8394 NO SW	ISL8394 NC SW
0	OFF	ON
1	ON	OFF

NOTE: Logic "0" $\leq$ 0.8V. Logic "1" $\geq$ 2.4V.
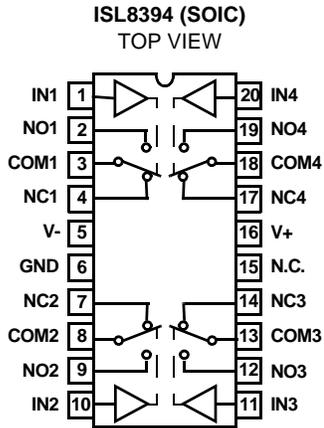
Pin Descriptions

PIN	FUNCTION
V+	Positive Power Supply Input
V-	Negative Power Supply Input. Connect to GND for Single Supply Configurations.
GND	Ground Connection
IN	Digital Control Input
COM	Analog Switch Common Pin
NO	Analog Switch Normally Open Pin
NC	Analog Switch Normally Closed Pin
N.C.	No Internal Connection

ISL8394

Absolute Maximum Ratings

V+ to V- . . . . -0.3 to15V
V+ to GND . . . . -0.3 to15V
V- to GND . . . . -15 to 0.3V
All Other Pins (Note 2). . . . . ((V-) - 0.3V) to ((V+) + 0.3V)
Continuous Current (Any Terminal) 30mA
Peak Current, IN, NO, NC, or COM
   (Pulsed 1ms, 10% Duty Cycle, Max) 100mA
ESD Rating (Per MIL-STD-883 Method 3015). . . . .>2kV

Thermal Information

Thermal Resistance (Typical, Note 3) θ_{JA} (^{o}C/W)
   20 Ld SOIC Package   95
Maximum Junction Temperature (Plastic Package) . . . . 150°C
Moisture Sensitivity (See Technical Brief TB363)
   SOIC Package . . . . Level 1
Maximum Storage Temperature Range. . . . . -65°C to 150°C
Maximum Lead Temperature (Soldering 10s) . . . . 300°C
   (Lead Tips Only)

Operating Conditions

Temperature Range
ISL8394IX . . . . -40°C to 85°C

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTES:

2. Signals on NC, NO, COM, or IN exceeding V+ or V- are clamped by internal diodes. Limit forward diode current to maximum current ratings.

3. θ_{JA} is measured with the component mounted on a low effective thermal conductivity test board in free air. See Tech Brief TB379 for details.

Electrical Specifications: ±5V Supply   Test Conditions: V_{SUPPLY} = ±4.5V to ±5.5V, GND = 0V, V_{INH} = 2.4V, V_{INL} = 0.8V (Note 4), Unless Otherwise Specified

PARAMETER	TEST CONDITIONS	TEMP (^{o}C)	(NOTE 5) MIN	TYP	(NOTE 5) MAX	UNITS
ANALOG SWITCH CHARACTERISTICS						
Analog Signal Range, V_{ANALOG}		Full	V-	-	V+	V
ON Resistance, R_{ON}	V_S = ±4.5V, I_{COM} = 10mA, V_{NO} or V_{NC} = ±3.5V, (See Figure 5)	25	-	17	35	Ω
		Full	-	-	45	Ω
R_{ON} Matching Between Channels, ΔR_{ON}	V_S = ±5V, I_{COM} = 10mA, V_{NO} or V_{NC} = ±3V	25	-	0.5	2	Ω
		Full	-	-	4	Ω
R_{ON} Flatness, $R_{FLAT(ON)}$	V_S = ±5V, I_{COM} = 10mA, V_{NO} or V_{NC} = ±3V, 0V, (Note 7)	25	-	-	4	Ω
		Full	-	-	6	Ω
NO or NC OFF Leakage Current, $I_{NO(OFF)}$ or $I_{NC(OFF)}$	V_S = ±5.5V, V_{COM} = ±4.5V, V_{NO} or V_{NC} = $\overline{+}$4.5V, (Note 6)	25	-0.2	-	0.2	nA
		Full	-2.5	-	2.5	nA
COM ON Leakage Current, $I_{COM(ON)}$	V_S = ±5.5V, V_{COM} = V_{NO} or V_{NC} = ±4.5V, (Note 6)	25	-0.4	-	0.4	nA
		Full	-5	-	5	nA
DIGITAL INPUT CHARACTERISTICS						
Input Voltage High, V_{INH}		Full	2.4	-	-	V
Input Voltage Low, V_{INL}		Full	-	-	0.8	V
Input Current, I_{INH}, I_{INL}	V_S = ±5.5V, V_{IN} = 0V or V+	Full	-1	-	1	μA
DYNAMIC CHARACTERISTICS						
Turn-ON Time, t_{ON}	V_S = ±4.5V, V_{NO} or V_{NC} = ±3V, R_L = 300Ω, C_L = 35pF, V_{IN} = 0 to 3V, (See Figure 1)	25	-	50	130	ns
		Full	-	-	175	ns
Turn-OFF Time, t_{OFF}	V_S = ±4.5V, V_{NO} or V_{NC} = ±3V, R_L = 300Ω, C_L = 35pF, V_{IN} = 0 to 3V, (See Figure 1)	25	-	30	75	ns
		Full	-	-	100	ns
Break-Before-Make Time Delay, t_D	V_S = ±5.5V, V_{NO} or V_{NC} = 3V, R_L = 300Ω, C_L = 35pF, V_{IN} = 0 to 3V, (See Figure 3)	25	2	10	-	ns
Charge Injection, Q	C_L = 1.0nF, V_G = 0V, R_G = 0Ω, (See Figure 2)	25	-	5	10	pC
NO OFF Capacitance, C_{OFF}	f = 1MHz, V_{NO} or V_{NC} = V_{COM} = 0V, (See Figure 7)	25	-	12	-	pF

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Electrical Specifications: ±5V Supply Test Conditions: V_{SUPPLY} = ±4.5V to ±5.5V, GND = 0V, V_{INH} = 2.4V, V_{INL} = 0.8V (Note 4), Unless Otherwise Specified **(Continued)**

PARAMETER	TEST CONDITIONS	TEMP (°C)	(NOTE 5) MIN	TYP	(NOTE 5) MAX	UNITS
NC OFF Capacitance, C_{OFF}	f = 1MHz, V_{NO} or V_{NC} = V_{COM} = 0V, (See Figure 7)	25	-	12	-	pF
COM ON Capacitance, $C_{COM(ON)}$	f = 1MHz, V_{NO} or V_{NC} = V_{COM} = 0V, (See Figure 7)	25	-	39	-	pF
OFF Isolation	R_L = 50Ω, C_L = 15pF, f = 1MHz, V_{NO} or V_{NC} = $1V_{RMS}$, (See Figures 4 and 6)	25	-	71	-	dB
Crosstalk, (Note 8)		25	-	-92	-	dB
POWER SUPPLY CHARACTERISTICS						
Power Supply Range		Full	±2.0	-	±6	V
Positive Supply Current, I+	V_S = ±5.5V, V_{IN} = 0V or V+, Switch On or Off	25	-1	0.01	1	μA
		Full	-1	-	1	μA
Negative Supply Current, I-		25	-1	0.01	1	μA
		Full	-1	-	1	μA

NOTES:

4. V_{IN} = Input voltage to perform proper function.

5. The algebraic convention, whereby the most negative value is a minimum and the most positive a maximum, is used in this data sheet.

6. Leakage parameter is 100% tested at high temp, and guaranteed by correlation at 25°C.

7. Flatness is defined as the difference between maximum and minimum value of on-resistance over the specified analog signal range. Flatness specifications are guaranteed only with specified voltages.

8. Between any two switches.

Electrical Specifications: 5V Supply Test Conditions: V+ = +4.5V to +5.5V, V- = GND = 0V, V_{INH} = 2.4V, V_{INL} = 0.8V (Note 4), Unless Otherwise Specified

PARAMETER	TEST CONDITIONS	TEMP (°C)	MIN (NOTE 5)	TYP	MAX (NOTE 5)	UNITS
ANALOG SWITCH CHARACTERISTICS						
Analog Signal Range, V_{ANALOG}		Full	0	-	V+	V
ON Resistance, R_{ON}	V+ = 5V, I_{COM} = 1.0mA, V_{NO} or V_{NC} = 3.5V, (See Figure 5)	25	-	25	65	Ω
		Full	-	-	75	Ω
R_{ON} Matching Between Channels, ΔR_{ON}	V+ = 5V, I_{COM} = 1.0mA, V_{NO} or V_{NC} = 3V	25	-	0.5	2	Ω
		Full	-	-	4	Ω
R_{ON} Flatness, $R_{FLAT(ON)}$	V+ = 5V, I_{COM} = 1.0mA, V_{NO} or V_{NC} = 1V, 2V, 3V, (Note 7)	25	-	-	6	Ω
		Full	-	-	8	Ω
NO or NC OFF Leakage Current, $I_{NO(OFF)}$ or $I_{NC(OFF)}$	V+ = 5.5V, V_{COM} = 1V, 4.5V, V_{NO} or V_{NC} = 4.5V, 1V, (Note 6)	25	-0.2	-	0.2	nA
		Full	-2.5	-	2.5	nA
COM ON Leakage Current, $I_{COM(ON)}$	V+ = 5.5V, V_{COM} = V_{NO} or V_{NC} = 4.5V, (Note 6)	25	-0.4	-	0.4	nA
		Full	-5	-	5	nA
DIGITAL INPUT CHARACTERISTICS						
Input Voltage High, V_{INH}		Full	2.4	-	-	V
Input Voltage Low, V_{INL}		Full	-	-	0.8	V
Input Current, I_{INH}, I_{INL}	V+ = 5.5V, V_{IN} = 0V or V+	Full	-1	-	1	μA
DYNAMIC CHARACTERISTICS						
Turn-ON Time, t_{ON}	V+ = 4.5V, V_{NO} or V_{NC} = 3V, R_L = 300Ω, C_L = 35pF, V_{IN} = 0 to 3V, (See Figure 1)	25	-	80	250	ns
		Full	-	-	300	ns

Electrical Specifications: 5V Supply Test Conditions: V+ = +4.5V to +5.5V, V- = GND = 0V, V_{INH} = 2.4V, V_{INL} = 0.8V (Note 4), Unless Otherwise Specified **(Continued)**

PARAMETER	TEST CONDITIONS	TEMP (°C)	MIN (NOTE 5)	TYP	MAX (NOTE 5)	UNITS
Turn-OFF Time, t_{OFF}	V+ = 4.5V, V_{NO} or V_{NC} = 3V, R_L = 300Ω, C_L = 35pF, V_{IN} = 0 to 3V, (See Figure 1)	25	-	40	125	ns
		Full	-	-	175	ns
Break-Before-Make Time Delay, t_D	V+ = 5.5V, V_{NO} or V_{NC} = 3V, R_L = 300Ω, C_L = 35pF, V_{IN} = 0 to 3V, (See Figure 3)	25	5	20	-	ns
Charge Injection, Q	C_L = 1.0nF, V_G = 0V, R_G = 0Ω, (See Figure 2)	25	-	3	5	pC
POWER SUPPLY CHARACTERISTICS						
Power Supply Range		Full	2	-	12	V
Positive Supply Current, I+	V+ = 5.5V, V- = 0V, V_{IN} = 0V or V+, Switch On or Off	25	-1	0.01	1	μA
		Full	-1	-	1	μA
Negative Supply Current, I-		25	-1	0.01	1	μA
		Full	-1	-	1	μA

Electrical Specifications: 3.3V Supply Test Conditions: V+ = +3.0V to +3.6V, V- = GND = 0V, V_{INH} = 2.4V, V_{INL} = 0.8V (Note 4), Unless Otherwise Specified

PARAMETER	TEST CONDITIONS	TEMP (°C)	MIN (NOTE 5)	TYP	MAX (NOTE 5)	UNITS
ANALOG SWITCH CHARACTERISTICS						
Analog Signal Range, V_{ANALOG}		Full	0	-	V+	V
ON Resistance, R_{ON}	V+ = 3V, I_{COM} = 1.0mA, V_{NO} or V_{NC} = 1.5V	25	-	75	185	Ω
		Full	-	-	250	Ω
NO or NC OFF Leakage Current, $I_{NO(OFF)}$ or $I_{NC(OFF)}$	V+ = 3.6V, V_{COM} = 0V, 4.5V, V_{NO} or V_{NC} = 3V, 1V, (Note 6)	25	-0.2	-	0.2	nA
		Full	-2.5	-	2.5	nA
COM ON Leakage Current, $I_{COM(ON)}$	V+ = 3.6V, V_{COM} = V_{NO} or V_{NC} = 3V, (Note 6)	25	-0.4	-	0.4	nA
		Full	-5	-	5	nA
DIGITAL INPUT CHARACTERISTICS						
Input Voltage High, V_{INH}		Full	2.4	-	-	V
Input Voltage Low, V_{INL}		Full	-	-	0.8	V
Input Current, I_{INH}, I_{INL}	V+ = 3.6V, V_{IN} = 0V or V+	Full	-1	-	1	μA
DYNAMIC CHARACTERISTICS						
Turn-ON Time, t_{ON}	V+ = 3.0V, V_{NO} or V_{NC} = 1.5V, R_L = 300Ω, C_L = 35pF, V_{IN} = 0 to 3V, (See Figure 1)	25	-	150	400	ns
Turn-OFF Time, t_{OFF}	V+ = 3.0V, V_{NO} or V_{NC} = 1.5V, R_L = 300Ω, C_L = 35pF, V_{IN} = 0 to 3V, (See Figure 1)	25	-	75	150	ns
Break-Before-Make Time Delay, t_D	V+ = 3.6V, V_{NO} or V_{NC} = 1.5V, R_L = 300Ω, C_L = 35pF, V_{IN} = 0 to 3V, (See Figure 3)	25	5	20	-	ns
Charge Injection, Q	C_L = 1.0nF, V_G = 0V, R_G = 0Ω, (See Figure 2)	25	-	1	5	pC
POWER SUPPLY CHARACTERISTICS						
Power Supply Range		Full	2	-	12	V
Positive Supply Current, I+	V+ = 3.6V, V- = 0V, V_{IN} = 0V or V+, Switch On or Off	25	-1	0.01	1	μA
		Full	-1	-	1	μA
Negative Supply Current, I-		25	-1	0.01	1	μA
		Full	-1	-	1	μA

Test Circuits and Waveforms

Logic input waveform is inverted for switches that have the opposite logic sense.

FIGURE 1A. MEASUREMENT POINTS

Repeat test for all switches. C_L includes fixture and stray capacitance.

$$V_{OUT} = V_{(NO\ or\ NC)} \frac{R_L}{R_L + R_{(ON)}}$$

FIGURE 1B. TEST CIRCUIT

FIGURE 1. SWITCHING TIMES

$$Q = \Delta V_{OUT} \times C_L$$
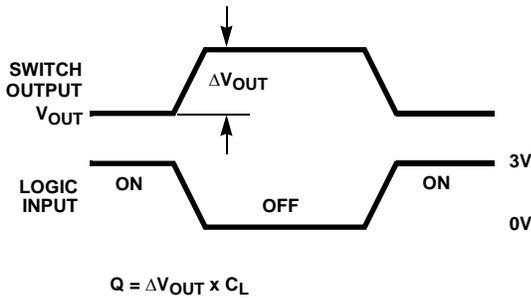
Logic input waveform is inverted for switches that have the opposite logic sense.

FIGURE 2A. MEASUREMENT POINTS

Repeat test for all switches. CL includes fixture and stray capacitance.

FIGURE 2B. TEST CIRCUIT

FIGURE 2. CHARGE INJECTION
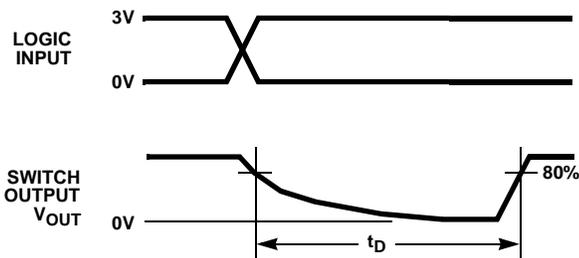
FIGURE 3A. MEASUREMENT POINTS

Repeat test for all switches. C_L includes fixture and stray capacitance.

FIGURE 3B. TEST CIRCUIT

FIGURE 3. BREAK-BEFORE-MAKE TIME

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Test Circuits and Waveforms (Continued)
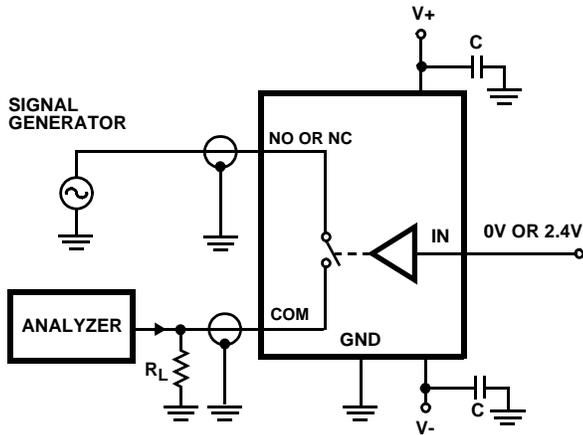
Repeat test for all switches.

FIGURE 4. OFF ISOLATION TEST CIRCUIT
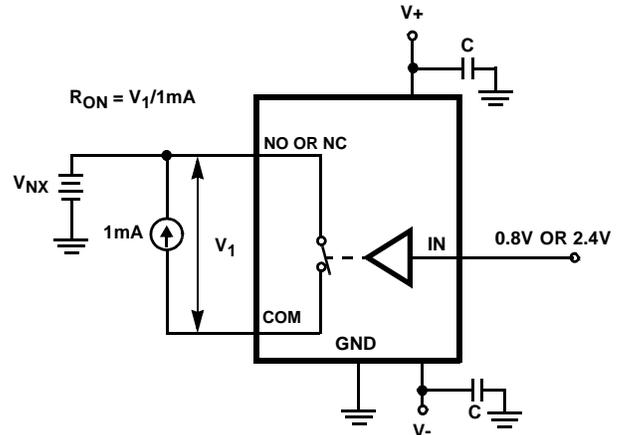
Repeat test for all switches.

FIGURE 5. R_{ON} TEST CIRCUIT
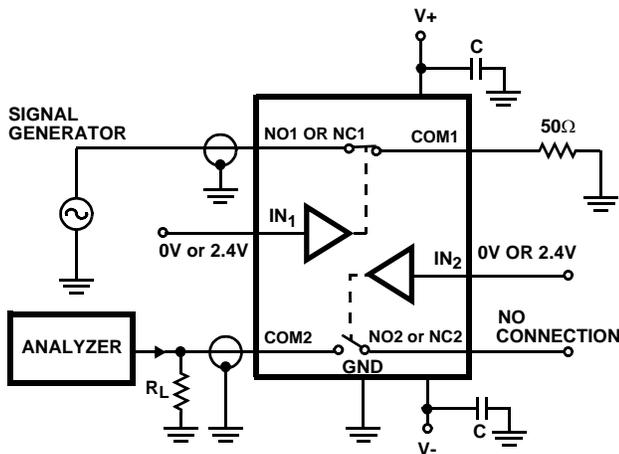
FIGURE 6. CROSSTALK TEST CIRCUIT
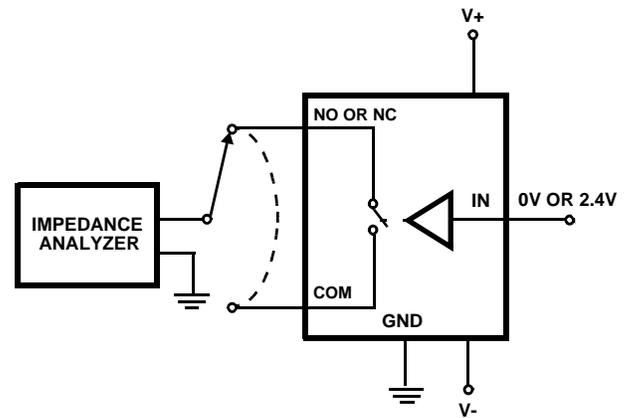
FIGURE 7. CAPACITANCE TEST CIRCUIT

Detailed Description

The ISL8394 quad analog switches offer precise switching capability from a bipolar ±2V to ±6V or a single 2V to 12V supply with low on-resistance (17Ω) and high speed operation (t_{ON} = 50ns, t_{OFF} = 30ns). The devices are especially well suited to portable battery powered equipment thanks to the low operating supply voltage (2V), low power consumption (5μW), low leakage currents (2.5nA max). High frequency applications also benefit from the wide bandwidth, and the very high off isolation and crosstalk rejection.

Supply Sequencing And Overvoltage Protection

With any CMOS device, proper power supply sequencing is required to protect the device from excessive input currents which might permanently damage the IC. All I/O pins contain ESD protection diodes from the pin to V+ and to V- (see

Figure 8). To prevent forward biasing these diodes, V+ and V- must be applied before any input signals, and input signal voltages must remain between V+ and V-. If these conditions cannot be guaranteed, then one of the following two protection methods should be employed.

Logic inputs can easily be protected by adding a 1kΩ resistor in series with the input (see Figure 8). The resistor limits the input current below the threshold that produces permanent damage, and the sub-microamp input current produces an insignificant voltage drop during normal operation.

Adding a series resistor to the switch input defeats the purpose of using a low R_{ON} switch, so two small signal diodes can be added in series with the supply pins to provide overvoltage protection for all pins (see Figure 8). These additional diodes limit the analog signal from 1V below V+ to

1V above V-. The low leakage current performance is unaffected by this approach, but the switch resistance may increase, especially at low supply voltages.
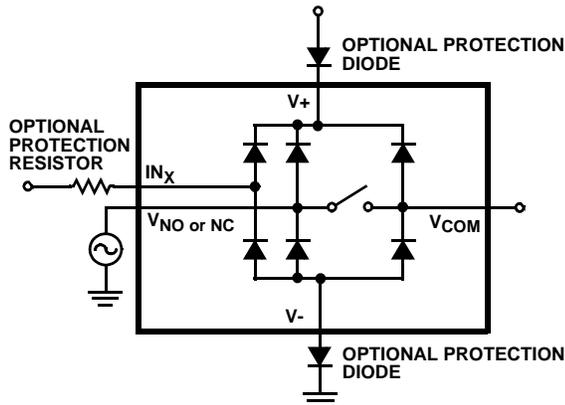

FIGURE 8. OVERVOLTAGE PROTECTION

Power-Supply Considerations

The ISL8394 construction is typical of most CMOS analog switches, in that they have three supply pins: V+, V-, and GND. V+ and V- drive the internal CMOS switches and set their analog voltage limits, so there are no connections between the analog signal path and GND. Unlike switches with a 13V maximum supply voltage, the ISL8394 15V maximum supply voltage provides plenty of room for the 10% tolerance of 12V supplies ($\pm$6V or 12V single supply), as well as room for overshoot and noise spikes.

This family of switches performs equally well when operated with bipolar or single voltage supplies.The minimum recommended supply voltage is 2V or $\pm$2V. It is important to note that the input signal range, switching times, and on-resistance degrade at lower supply voltages. Refer to the electrical specification tables and *Typical Performance* curves for details.

V+ and GND power the internal logic (thus setting the digital switching point) and level shifters. The level shifters convert the logic levels to switched V+ and V- signals to drive the analog switch gate terminals.

Logic-Level Thresholds

V+ and GND power the internal logic stages, so V- has no affect on logic thresholds. This switch family is TTL compatible (0.8V and 2.4V) over a V+ supply range of 2.7V to 10V. At 12V the V_{IH} level is about 2.5V. This is still below the TTL guaranteed high output minimum level of 2.8V, but noise margin is reduced. For best results with a 12V supply, use a logic family that provides a V_{OH} greater than 3V.

The digital input stages draw supply current whenever the digital input voltage is not at one of the supply rails. Driving the digital input signals from GND to V+ with a fast transition time minimizes power dissipation.

High-Frequency Performance

In 50Ω systems, signal response is reasonably flat even past 200MHz (see Figure 15), with a small signal -3dB bandwidth in excess of 300MHz, and a large signal bandwidth exceeding 300MHz.

An off switch acts like a capacitor and passes higher frequencies with less attenuation, resulting in signal feedthrough from a switch's input to its output. Off Isolation is the resistance to this feedthrough, while Crosstalk indicates the amount of feedthrough from one switch to another. Figure 16 details the high Off Isolation and Crosstalk rejection provided by this switch. At 10MHz, off isolation is about 50dB in 50Ω systems, decreasing approximately 20dB per decade as frequency increases. Higher load impedances decrease Off Isolation and Crosstalk rejection due to the voltage divider action of the switch OFF impedance and the load impedance.

Leakage Considerations

Reverse ESD protection diodes are internally connected between each analog-signal pin and both V+ and V-. One of these diodes conducts if any analog signal exceeds V+ or V-.

Virtually all the analog leakage current comes from the ESD diodes to V+ or V-. Although the ESD diodes on a given signal pin are identical and therefore fairly well balanced, they are reverse biased differently. Each is biased by either V+ or V- and the analog signal. This means their leakages will vary as the signal varies. The difference in the two diode leakages to the V+ and V- pins constitutes the analog-signal-path leakage current. All analog leakage current flows between each pin and one of the supply terminals, not to the other switch terminal. This is why both sides of a given switch can show leakage currents of the same or opposite polarity. There is no connection between the analog signal paths and GND.

Typical Performance Curves $T_A = 25^oC$, Unless Otherwise Specified
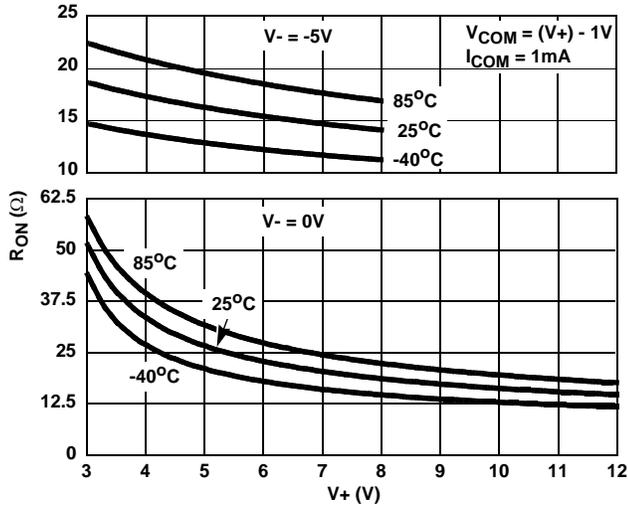
FIGURE 9. ON RESISTANCE vs SUPPLY VOLTAGE
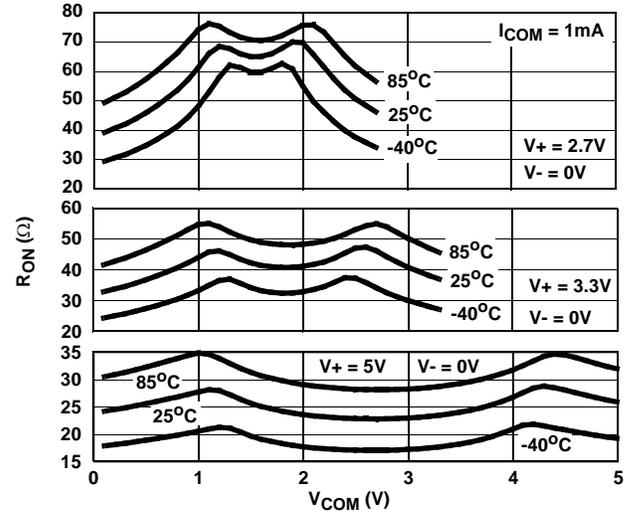

FIGURE 10. ON RESISTANCE vs SWITCH VOLTAGE
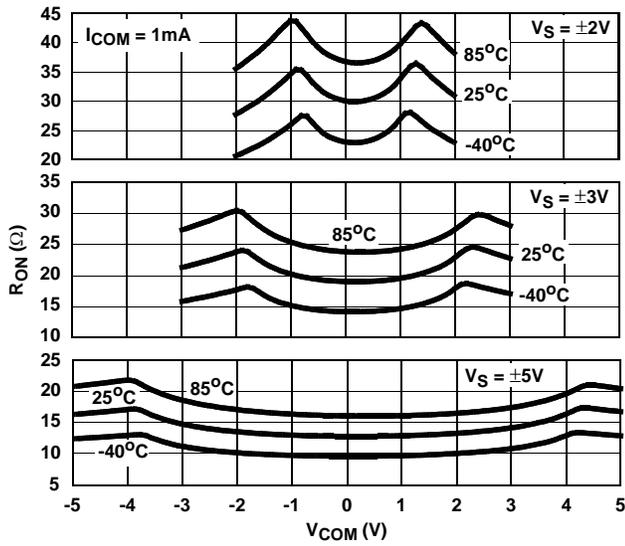
FIGURE 11. ON RESISTANCE vs SWITCH VOLTAGE
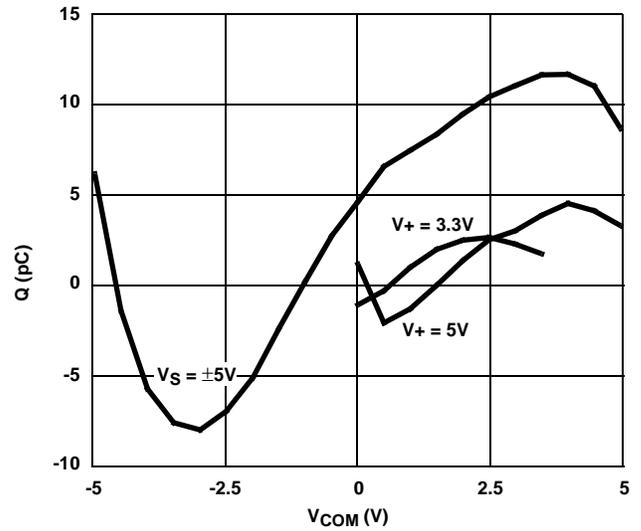
FIGURE 12. CHARGE INJECTION vs SWITCH VOLTAGE

Typical Performance Curves T_A = 25°C, Unless Otherwise Specified **(Continued)**
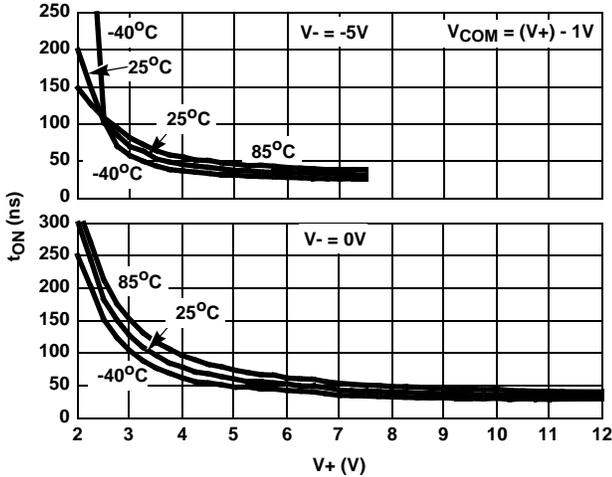
FIGURE 13. TURN - ON TIME vs SUPPLY VOLTAGE
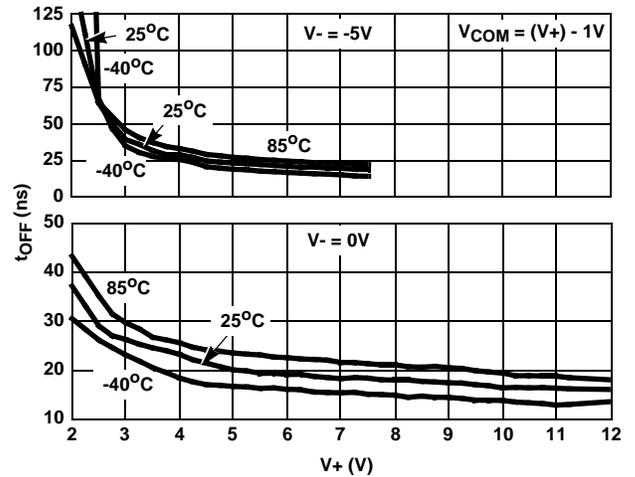
FIGURE 14. TURN - OFF TIME vs SUPPLY VOLTAGE
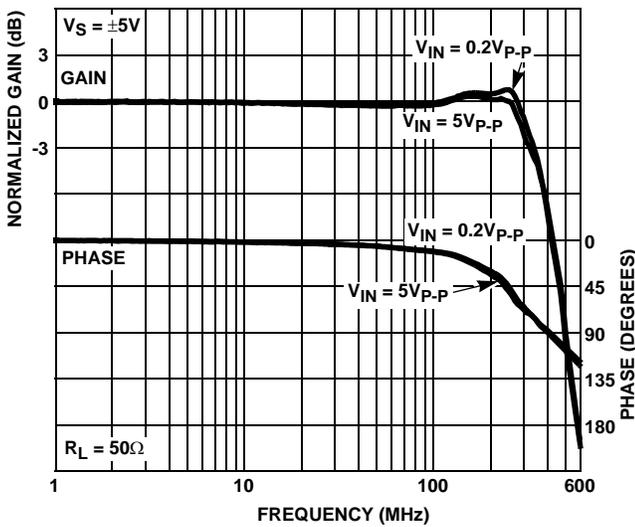
FIGURE 15. FREQUENCY RESPONSE
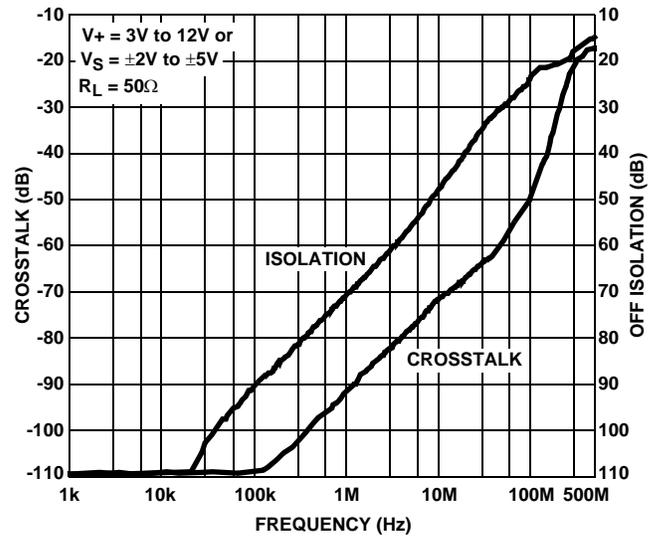
FIGURE 16. CROSSTALK AND OFF ISOLATION

Die Characteristics

SUBSTRATE POTENTIAL (POWERED UP):

GND

TRANSISTOR COUNT:

ISL8394: 418

PROCESS:

Si Gate CMOS

Small Outline Plastic Packages (SOIC)
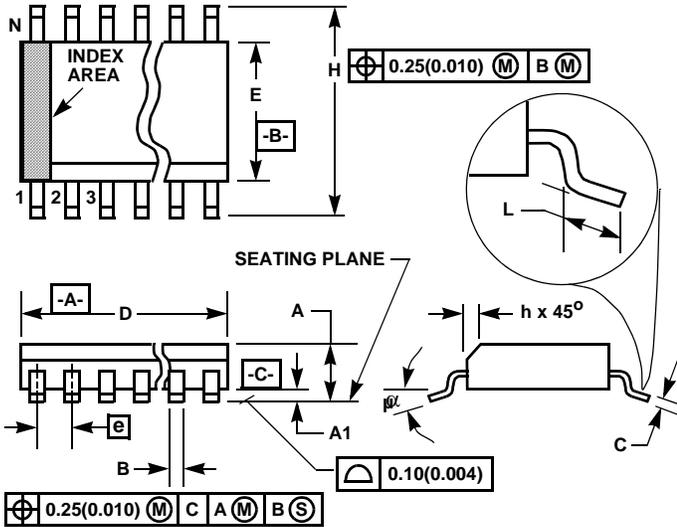
M20.3 (JEDEC MS-013-AC ISSUE C)
20 LEAD WIDE BODY SMALL OUTLINE PLASTIC PACKAGE

SYMBOL	INCHES		MILLIMETERS		NOTES
	MIN	MAX	MIN	MAX	
A	0.0926	0.1043	2.35	2.65	-
A1	0.0040	0.0118	0.10	0.30	-
B	0.014	0.019	0.35	0.49	9
C	0.0091	0.0125	0.23	0.32	-
D	0.4961	0.5118	12.60	13.00	3
E	0.2914	0.2992	7.40	7.60	4
e	0.050 BSC		1.27 BSC		-
H	0.394	0.419	10.00	10.65	-
h	0.010	0.029	0.25	0.75	5
L	0.016	0.050	0.40	1.27	6
N	20		20		7
α	0°	8°	0°	8°	-

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NOTES:

1. Symbols are defined in the "MO Series Symbol List" in Section 2.2 of Publication Number 95.

2. Dimensioning and tolerancing per ANSI Y14.5M-1982.

3. Dimension "D" does not include mold flash, protrusions or gate burrs. Mold flash, protrusion and gate burrs shall not exceed 0.15mm (0.006 inch) per side.

4. Dimension "E" does not include interlead flash or protrusions. Interlead flash and protrusions shall not exceed 0.25mm (0.010 inch) per side.

5. The chamfer on the body is optional. If it is not present, a visual index feature must be located within the crosshatched area.

6. "L" is the length of terminal for soldering to a substrate.

7. "N" is the number of terminal positions.

8. Terminal numbers are shown for reference only.

9. The lead width "B", as measured 0.36mm (0.014 inch) or greater above the seating plane, shall not exceed a maximum value of 0.61mm (0.024 inch)

10. Controlling dimension: MILLIMETER. Converted inch dimensions are not necessarily exact.

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